

X-ray multilayers for diffractometers, monochromators, and spectrometers - 17-19 August 1988, San Diego, California

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Description: -

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X-ray diffractometer -- Surfaces -- Congresses.

Spectrometer -- Surfaces -- Congresses.

Monochromator -- Surfaces -- Congresses.

X-rays -- Congresses.

Thin films, Multilayered -- Congresses. X-ray multilayers for diffractometers, monochromators, and spectrometers - 17-19 August 1988, San Diego, California

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v. 984.

Proceedings of SPIE--the International Society for Optical Engineering ;

v. 984

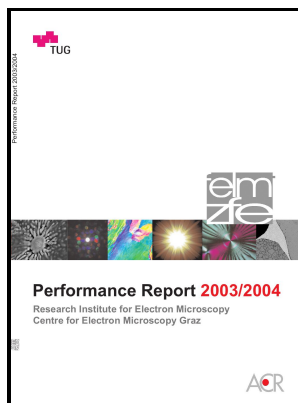
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; X-ray multilayers for diffractometers, monochromators, and

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Advances in Imaging and Electron Physics, Volume 132 (Advances in Imaging and Electron Physics)

The method is based on the adaptive weights method with conjugate gradient. The sum of the eigenvalues is called the energy of the system: $E_{\text{DUP}} = \frac{1}{4} d \sum_{j=1}^5 |j|$.

Items where Subject is Science > QC

To construct an accurate space charge model of the grain boundary region, the true structure of the grain boundary interface must be known. Seiler Semiconductor Electronics Division, National Institute of Standards and Technology, Gaithersburg, Maryland CHAP.

Thin

Unpublished Zhang, Peng, Li, Jie, Yu, Guoyu and Walker, David D. Analisi Numerica: Metodi, Modelli, Applicazioni. Spatial Difference Technique for Examining Boundaries.

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The Fourier transform of the regularly sampled signal has the same shape as that of the original Fourier transform, but the peaks are slightly lower the signal loses some energy and the higher frequencies are missing. A listing of definitions for each of these terms follows: creep strength: the stress that will cause a given time-dependent plastic strain in a creep test for a given time. Therefore, viewing Pr_{11} as a map from V to V_{1r} , we have that $1 \times r \times P \times \text{DUP} \times Pr_{11} \times \text{DUP} ; \delta 4:3 \times Br \times \frac{1}{4} jGkUj \times gu \times 11$ and therefore Br can be viewed as the covariance matrix of the projected symmetrized data.

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One should be able to connect any point in the high-index material to any other point without having to cross over into the low-index material.

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To complete the KL analysis of a particular data set in this vector space, we would have to follow the algorithm from step 2 on step 1 was completed in this section.

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They are given in Berkooz and Titi 1993 and Dellnitz et al. The method based on NDFT, presented in Section III. Note that this symmetry assumption is not that each pattern in U is G -invariant; only that a translate of a pattern is again a possible pattern.

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